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Lattice-matched III-V solar cells: progress and application opportunities

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CS International Conference, April 16th-17th 2024, Brussels



Outline

- Motivation
- Epitaxy of lattice-matched GaInNAsSb heterostructures on GaAs
 - State-of-the-art 0.7-0.8 eV junctions
- Progress in developing 4J/5J/6J lattice-matched solar cells
- Forward looking conclusions





Motivation

Multijunction III–V solar cells

- Key technology for space solar power
- Terrestrial applications in CPV systems

The quest for higher efficiencies

- Reduced weight/power ratio for satellites
- Increased economic feasibility for CPV

Standard monolithic technology limited to 4J architectures (MOCVD based; requires thick metamorphic buffers)

Advanced functionality: thin-film flexible solar cells (proven for lattice-matched architectures)



Flexible solar cells are needed on the ROSA (Roll Out Solar Array) held by the robotic arms at the International Space Station. CS Mag. Oct. 2021



R. France et al,. MRS Bulletin, Mar. 2016





Key issues: material quality and current-matching



Adapted from Hirst, Ekins-Daukes: Fundamental losses in solar cells," *Prog. in PV: Res. and App.*, 2011



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Established by the European Commission



Bandgap engineering with dilute nitrides



Reaching 0.7-0.8 eV on GaAs requires 6-8% of nitrogen

MBE growth of 1 eV GalnNAsSb junctions



CS International 2024



4J cells with two GalnNAsSb junctions



4J with two dilute nitride bottom junctions

Aho et al., Prog Photovolt Res Appl. 29: 869-875 (2021)



Lattice-matched designs with 5+ junctions

- Extension to long wavelength using GalnNAsSb junctions with E_{a} <0.9 eV ([N] >5%)
- Current matching also requires development of AlGaInP top junction (>2 eV)



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Epitaxy optimization of 0.8 eV GalnNAsSb

- Lattice-matched high-N p-i-n junctions grown on 4" p-GaAs
- E_g target~0.8 eV (N ~5-6%; In ~ 15%; Sb ~2-3%)
- Change of growth parameters: T_g , As/III BEP ratio, Sb flux
- All samples in-situ annealed

	Sample	[In] _{nominal}	[N] _{nominal}	T_{g}	As/III BEP	Sb BEP
		(%)	(%)	(°C)	ratio	(Torr)
T _g	A	15	5.2	440	9.0	1.0×10 ⁻⁸
	В	15	5.7	440	9.0	1.0×10 ⁻⁸
	С	15	5.2	450	9.0	1.0×10 ⁻⁸
	D	15	5.2	460	9.0	1.0×10 ⁻⁸
	E	15	5.0	470	9.0	1.0×10 ⁻⁸
	F F	15	5.0	480	9.0	1.0×10 ⁻⁸
As	G	15	5.0	470	7.0	1.0×10 ⁻⁸
	Н	15	4.9	470	5.2	1.0×10 ⁻⁸
Sb		15	4.8	470	7.0	1.4×10 ⁻⁸
	J	14	4.8	470	7.0	1.8×10 ⁻⁸
	K	14	4.8	480	7.0	1.8×10 ⁻⁸

n-GaAs	300 nm	$1\times10^{19}\mathrm{cm}^{\text{-3}}$	Contact layer
n-Al _{0.35} Ga _{0.65} As	40 nm	$2\times10^{18}\mathrm{cm}^{\text{-3}}$	Window
n-GaAs	100 nm	$1\times10^{18}\mathrm{cm}^{\text{-3}}$	Emitter
i-GaInNAsSb	1.2 µm		Absorber
p-GaAs	100 nm	$5 \times 10^{18} \mathrm{cm}^{-3}$	Base
p-GaAs p-Al _{0.35} Ga _{0.65} As	100 nm 100 nm	$5 \times 10^{18} \mathrm{cm}^{-3}$ $5 \times 10^{18} \mathrm{cm}^{-3}$	Base BSF
p-GaAs p-Al _{0.35} Ga _{0.65} As p-GaAs	100 nm 100 nm 300 nm	$\frac{5 \times 10^{18} \mathrm{cm^{-3}}}{5 \times 10^{18} \mathrm{cm^{-3}}}$ $5 \times 10^{18} \mathrm{cm^{-3}}$	Base BSF Buffer

Isoaho et al., Sol. Energy Mater. Sol. Cells (2022)



Effects of growth parameters



T_g \uparrow :

- Enhanced N incorporation at \geq 460 °C
 - More recombination with higher N
 - Carrier lifetimes 4-5 ns \rightarrow < 1 ns
 - Reduction of V_{oc}
- Phase separation at 480°C
 - Suppressed with more Sb
- p-type background doping \downarrow
 - $10^{17} \text{ cm}^{-3} \rightarrow 10^{16} \text{ cm}^{-3}$
 - EQE and $J_{\rm sc}$ \uparrow



As ↓:

- Enhanced N and Sb incorporation
 - More recombination with higher N
 - Carrier lifetimes 1.5 ns \rightarrow 0.5 ns
 - Reduction for V_{oc}
- p-type background doping ↓
 - $2 \cdot 10^{16} \text{ cm}^{-3} \rightarrow 2 \cdot 10^{15} \text{ cm}^{-3}$
 - EQE and $J_{\rm sc}$ \uparrow
 - >90% EQE values achieved



Sb ↑:

- Slight reduction in recombination
 - Carrier lifetimes 0.6 ns \rightarrow 0.7 ns
 - +20 mV for V_{oc}
- p-type background doping ↑
 - $2 \cdot 10^{15} \, \text{cm}^{-3} \rightarrow 7 \cdot 10^{15} \, \text{cm}^{-3}$
 - EQE and $J_{sc} \downarrow$
- Combined effect \rightarrow +10% in output power with intermediate Sb

Isoaho et al., Sol. Energy Mater. Sol. Cells (2022)



LM MJSCs: From 3 to 6 junctions



Measured LIV characteristics for lattice-matched solar cells under 500 x AM1.5D illumination.

LMSC	J _{sc-meas} /J _{sc-target} (mA/cm²)	V _{oc} (V)	Eg (eV)
3J	13/14	3.1	1.9/1.4/1.0
4J	11/12	4.1	1.9/1.4/1.2/0.9
5J	6/9	5.1	1.9/1.7/1.4/1.1/0.9
6J	6/8	5.3	1.9/1.7/1.4/1.2/1.1/0.8



5J:GalnP/AlGaAs/GaAs/GalnNAsSb/GalnNAsSb

- 6 layers ARC coating
- Good voltage per junction
 W_{oc} (500x) = 0.39 V (similar to LM3J)
- Small cell area of 0.04 cm²
- EQE: Bottom SC limits the Jsc
 - Too large E_g (6 mA/cm² vs. 9 mA/cm²)





Prospects for 6J integration

- Current-matching for ~0.8 eV sub-cells is achievable
- Concentrated efficiencies exceeding 50% are realistic with 6J employing the best experimental 0.78 eV GaInNAsSb junctions (top junction require larger bandwidth)



Technology compatible with MOCVD



ORC, Tampere (VEECO GEN20 MBE)

CESI, MILAN (VEECO 450 MOCVD)

Growth on 100 mm GaAs (100) substrate

Combines the technological and economic advantages of both the MBE and MOCVD processes to produce MJ solar cells at reduced cost and higher throughput with respect to MBE process.

Key issues: transfer process; nucleation layers; MOCVD thermal budget

A. Tukiainen at al., **High-efficiency GalnP/GaAs/GalnNAs solar cells** grown by combined MBE-MOCVD technique; 2016

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MBE/MOCVD on Ge substrate





$InGaP (E_g = 1.85 \text{ eV}) \qquad 4. \text{ GaInP SC and interfaces}$ $3. \text{ GaInAs SC and interfaces} \qquad InGaAs (E_g = 1.38 \text{ eV})$ $InGaNAs (E_g = 1 \text{ eV}) \qquad 2. \text{ InGaNAs SC and interfaces}$ $1. \text{ n-Ge emitter nucleation} \qquad Ge (E_g = 0.67 \text{ eV})$

Public report ESA Project "Impro33"

Fig. 2: Basic principle of the combined MBE-MOCVD technique.





Forward looking conclusions

- MBE technology for dilute-nitride solar cells is mature enough for architectures with more than 4 junctions. Suitable for mass production.
- High quality low-bandgap GaInNAsSb materials (N ~ 6%) demonstrated.
- The highest bandgap junction needs to be developed as well as several processing aspects (e.g., grid design, passivation, ARC, mounting etc.)
- The 50% efficiency target under CPV conditions is feasible.
- Lattice-matched solar cell technology is particularly attractive for implementing thin-film architectures for specialized applications.



From materials to applications





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European Research Council Established by the European Commission

Financial support: ERC AdG project AMETIST (ERC-2015-AdG 695116)



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